



# AEMtec

## State of the art and novel wafer level solder bumping techniques

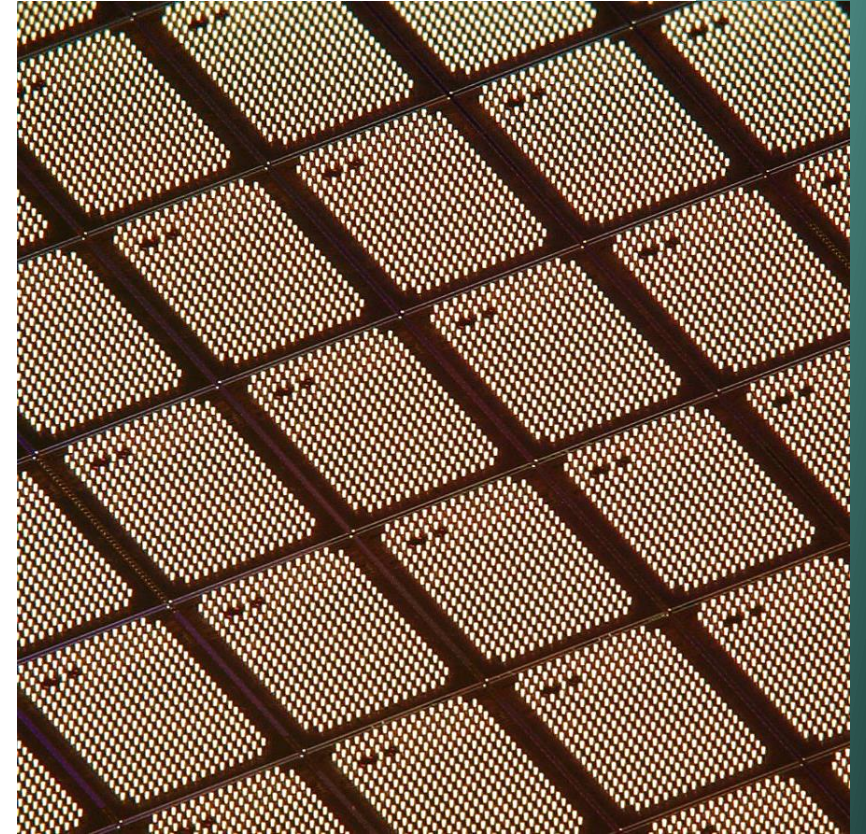
D.Lieske, 13.06.2023

37th Chemnitz Seminar  
»Electronic Packaging and Applications«

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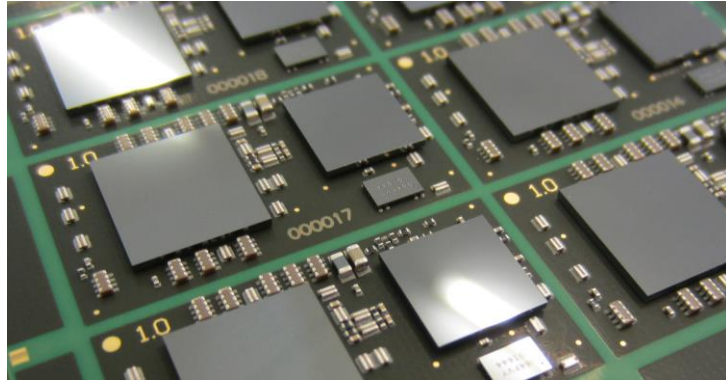
# Wafer level bumping..

- is solder bump formation on wafer
- is state of the art for flip chip packaging process
- is the first choice for heterogeneous integration today
- has advantages compared to wire bonding e.g. high pin count, higher signal speed, faster for high volume
- is required for many more applications like Wafer Level Package, FanOut WLP or C2W (Chip to Wafer) and chiplet
- the demand is growing for the next decade

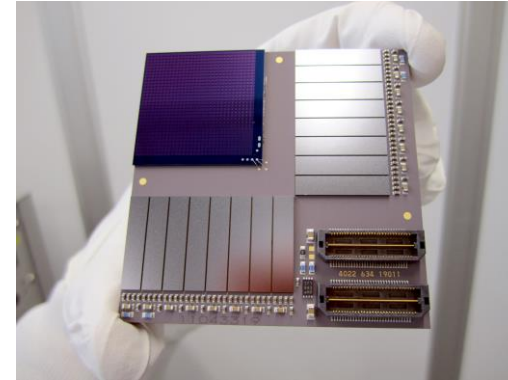


# Heterogeneous integration examples

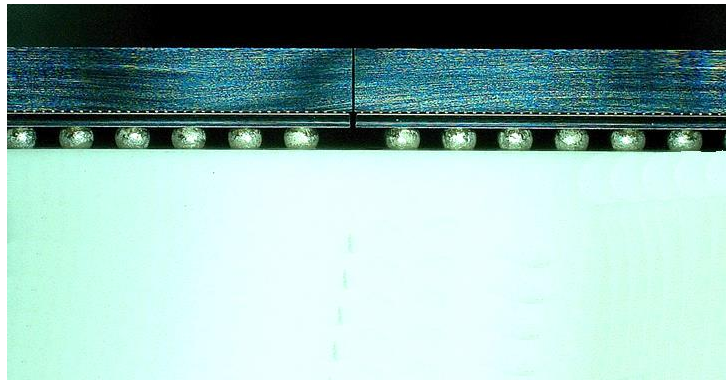
- SiP



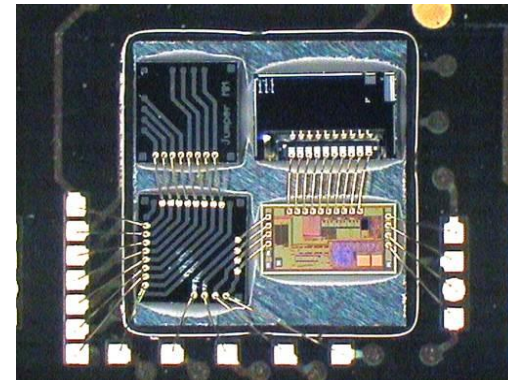
- MEMS



- X-Ray



- Sensors



# Wafer level bumping – a brief introduction

- Requires a UBM solderable pad surface like NiAu, NiPdAu or Copper
- Contact pitch depending on contact size (400 $\mu$ m...60 $\mu$ m) down to 130 $\mu$ m +/-
- Chip to substrate, RDL interposer or Chip to chip interconnections (e.g. Bunch of wires) possible
- High pin count require fast process solutions, wire bonding for 500+ interconnects is not the best solution for Mass production
- Applications are for computing in nearly every new application and every market segment, (Asic controller, RF applications, image and signal processing,...)

# Wafer level bumping process methods

## With solder alloys

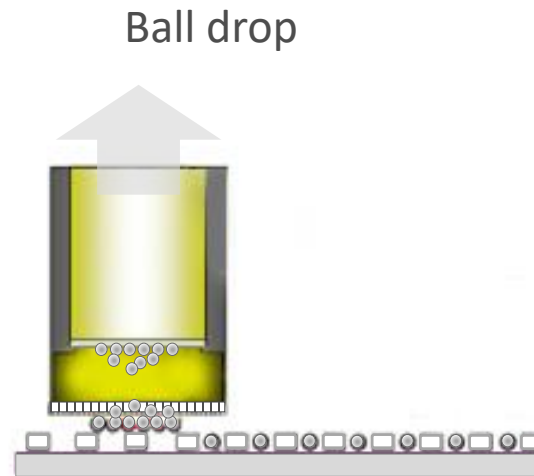
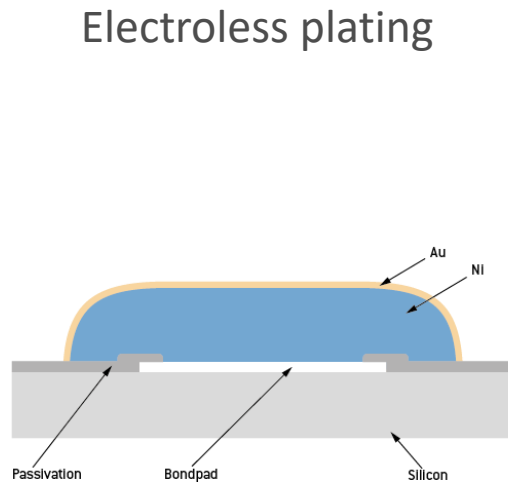
- UBM + Ball drop (very flexible, fast and less costly, any alloy types, large and small pitch, all SAC, low melting (BiSn, InSn48) and high melting (PbSn10))
- UBM + C4 electroplating (ball or copper pillar bumps, requires lithography, lowest pitch, limited alloy types)
- Solder printing

## Others

- Au stud bumping (flexible, low cost, thermocompression)
- Electroless Nickel or NiAu bumping (small pitch, thermocompression e.g. ACF)

# Wafer level bumping with Ball drop process

- Process is capable up to 3 Mio bumps per Wafer for 6 – 12 inch wafer



Qualified\*1)

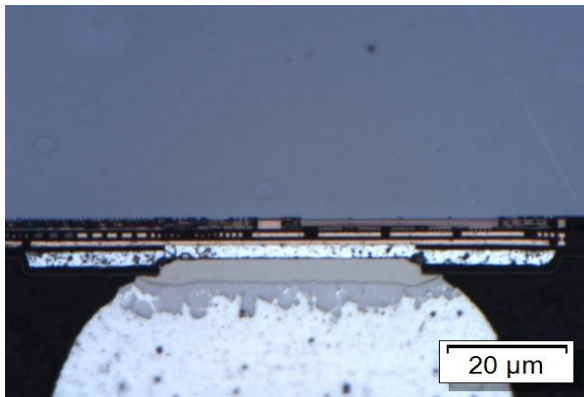
Method	Parameter	Duration	Rsult
Temperature Cycle Test	$T_{high} = 125^{\circ}\text{C}$ $T_{low} = -55^{\circ}\text{C}$	2000 cycles	✓
High Temperature Storage	$T = 150^{\circ}\text{C}$	1000 hours	✓
Temperature Humidity Storage	$T = 85^{\circ}\text{C}$ $\Phi = 85\% \text{ r. H.}$	1000 hours	✓

\*1) UBM and Wafer level bumping is a qualified process, additionally it has to qualified via package qualification, depending on solder alloy type and application

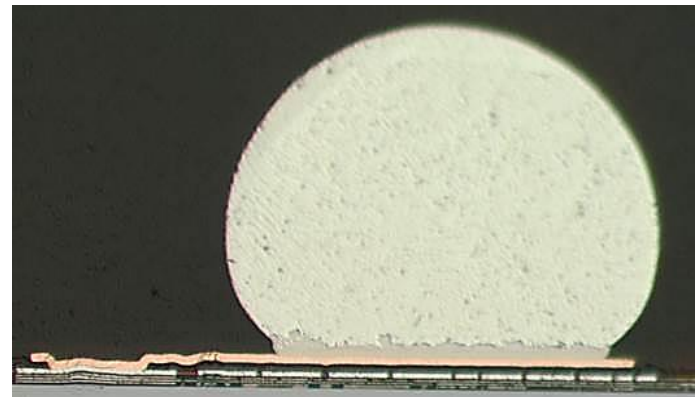
# Typical Combinations of UBM and Solder

- UBM (electroless plating) and solder bumping AEMtec
- UBM (Electroplating) with or without RDL and solder bumping AEMtec
- UBM (Electroplating) solder bumping via plating other OSAT's

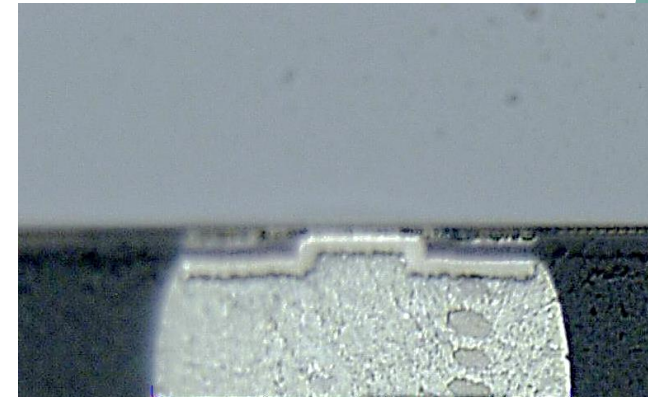
Electroless UBM + Ball drop  
(AEMtec)



RDL + Ball drop  
(AEMtec)



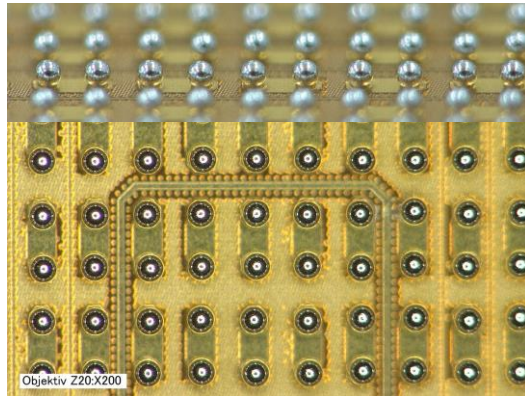
Electroplating UBM + Electroplating Solder  
(other)



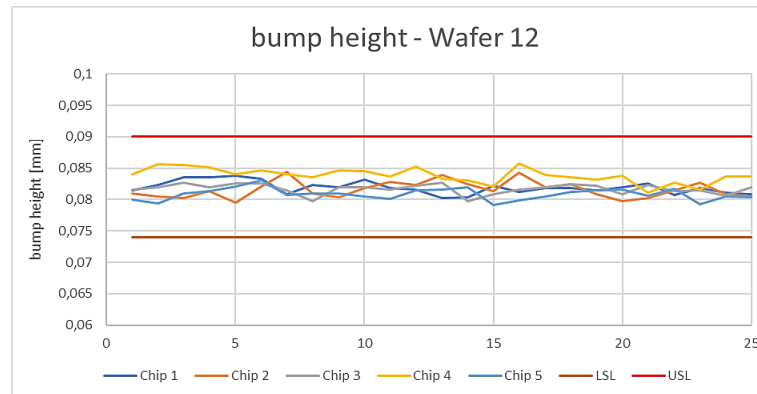
# Properties of Solder bumping and results

## Benefits

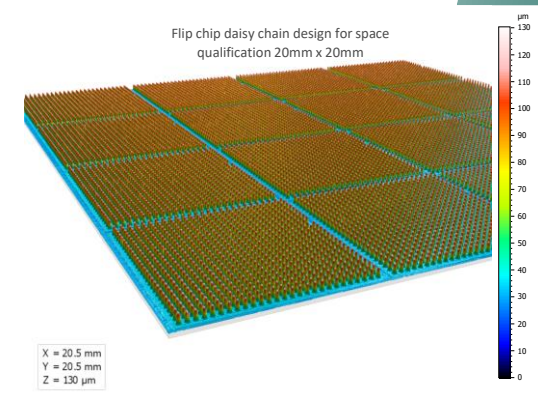
- Fast process, no plating chemistry
- Accurate solder bump positions before reflow
- Stable bump height after soldering due to precise preform spheres



bump position before soldering



bump height distribution within  $\pm 5\mu\text{m}$  (95 $\mu\text{m}$  ball diameter)





# Properties of Solder bumping and results

## Benefits

- Any solder alloy possible, fast exchange of allow type, fast product change
- Process is capable for double sided wafer with surface on backside which must not get into contact with liquids

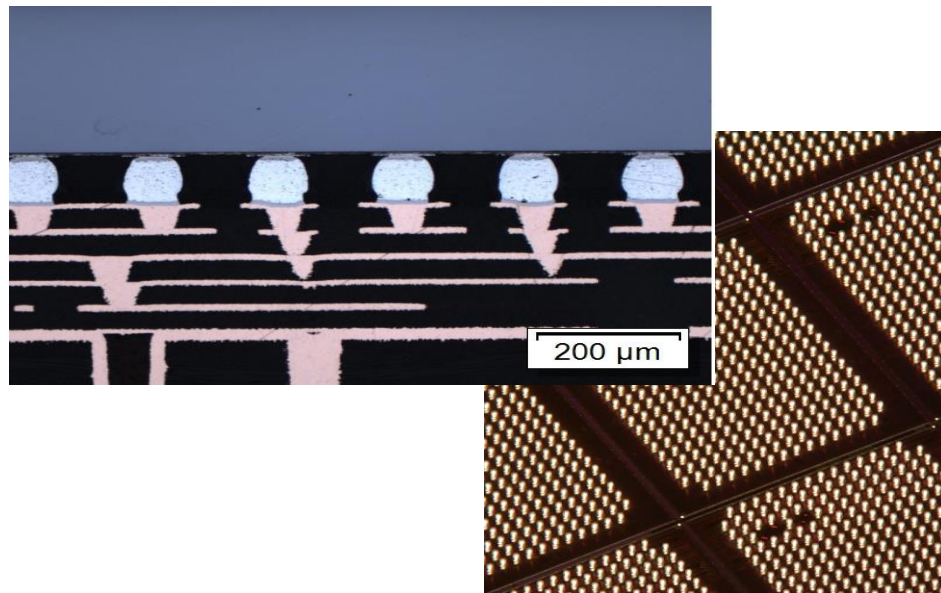
## Con

- Flux cleaning required for water soluble flux or no clean flux possible without cleaning\*1)

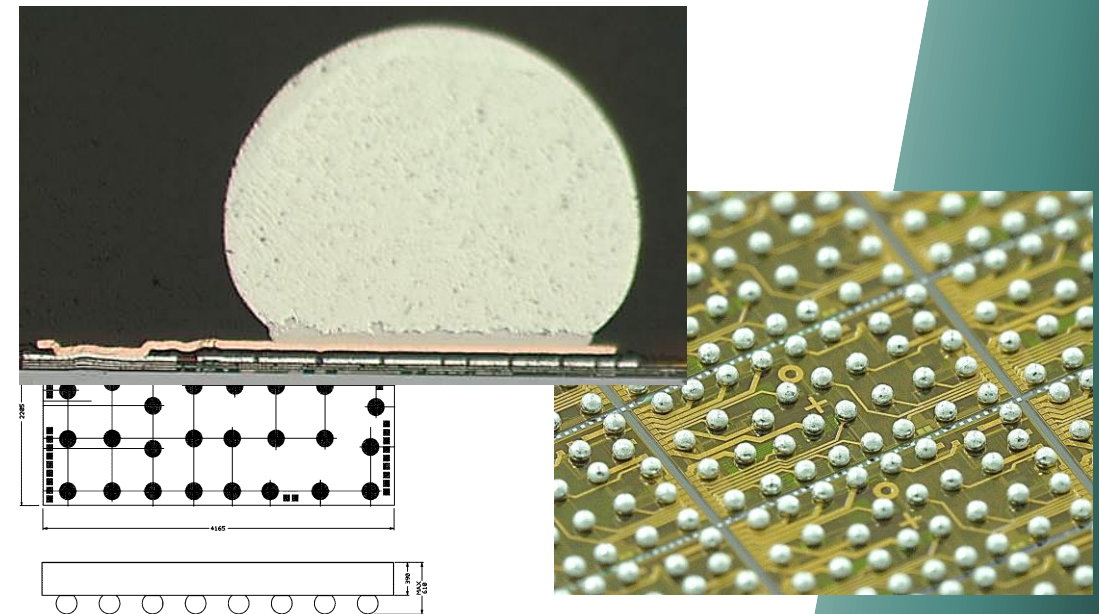
\*1) No clean flux requires qualification with final product assembly process

# Basic Applications

- Flip Chip package



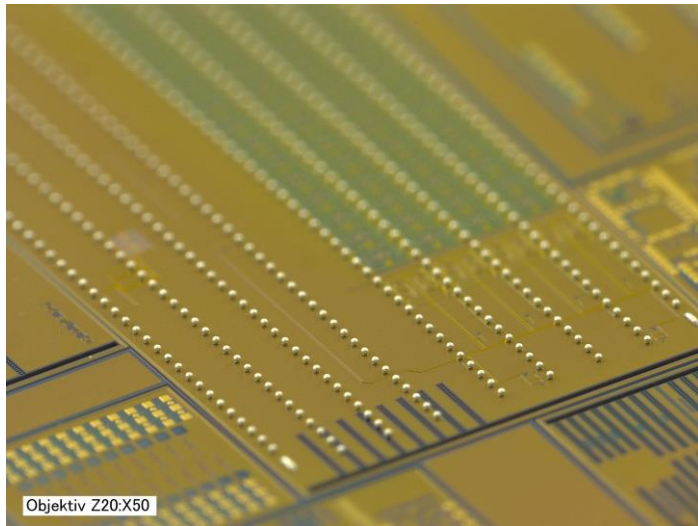
- WL-CSP



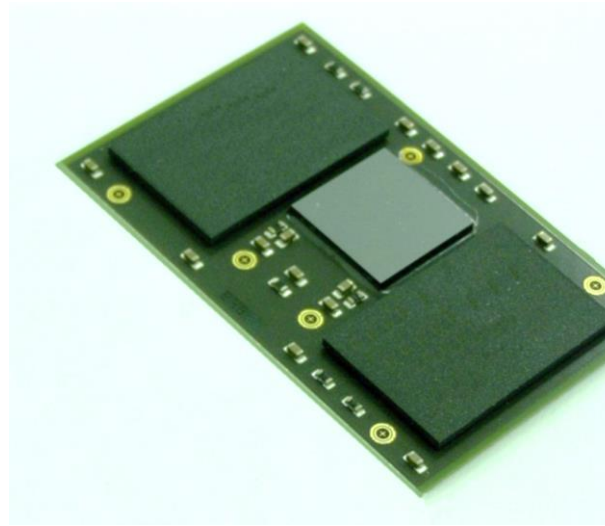
- Application: SIP/ MCM, Flip Chip package, RF package, Smart systems (optical-, gas-, liquid-, sensors, accelerometers,...), telecommunication, bit coin, medical, ...

# Novel Applications

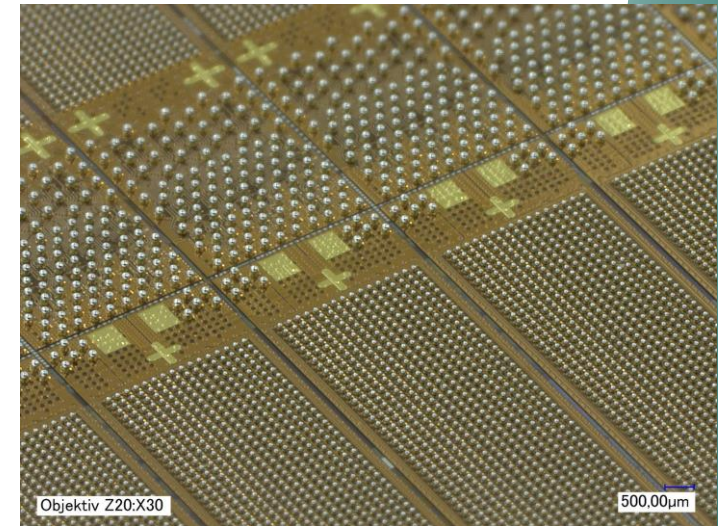
- Silicon photonics



- ADAS

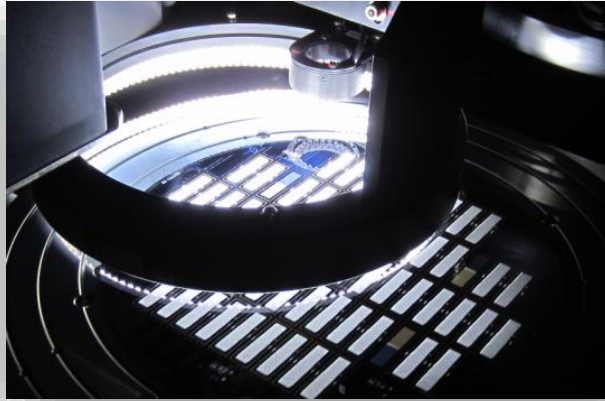
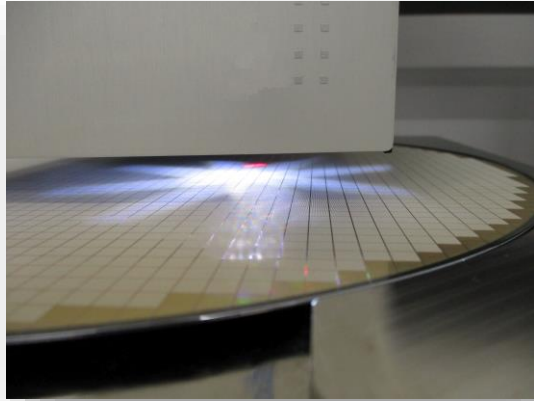


- MEMS



- Different solder sphere diameter on the same wafer is possible <sup>\*new)</sup>
- Photonics SIP, HPC (high bandwidth, high speed) AI, autonomous driving, CdTe sensors

# Unique wafer level bumping & Semiconductor packaging in Europe



# AEMtec Network in Europe & worldwide



- ✓ Central Position in Europe
- ✓ Worldwide Customer Network
- ✓ Strong Institutes Network
- ✓ Strong Foundry Network



# Your Strategic Technology Partner

**THANK YOU!**



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